	Applic
Issue Classification	09466
	Exami
	Maikha

Application/Control No.	Applicant(s)/Patent Under Reexamination
09466627	LO ET AL.
Examiner	Art Unit
Maikhanh Nguyen	2176

ORIGINAL							INTERNATIONAL CLASSIFICATION									
CLASS SUBCLASS						CLAIMED						NON-CLAIMED				
715 234				G	0	6	F	17 / 00 (2006.01.01)								
CROSS REFERENCE(S)					G	0	6	F	7 / 00 (2006.01.01)							
CLASS	SI	UBCLASS (ON	E SUBCLAS	S PER BLC	CK)											
715	230	713														
707	1	100														
	1															
	<u> </u>															
	I															

☐ Claims renumbered in the same order as presented by applicant ☐									СР	Α [R.1.	R.1.47			
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
1	1		17		33		49		65		81	12	97		
	2		18	11	34		50		66		82	18	98		
	3	4	19		35		51		67		83		99		
	4		20		36		52		68	16	84		100		
	5	5	21	13	37		53		69		85				
	6	6	22		38		54		70		86				
2	7		23		39		55		71	17	87				
	8		24	14	40		56		72		88				
	9	7	25		41		57		73		89				
	10		26		42		58		74	3	90				
	11	8	27	15	43		59		75		91				
	12	9	28		44		60		76		92				
	13		29		45		61		77		93				
	14		30		46		62		78		94				
	15	10	31		47		63		79		95				
	16		32		48		64		80		96				

/Maikhanh Nguyen/ Examiner.Art Unit 2176	09/10/08	Total Claims Allowed:			
(Assistant Examiner)	(Date)				
/Doug Hutton/ Supervisory Patent Examiner, Technology Center 2100	9/15/08	O.G. Print Claim(s)	O.G. Print Figure		
(Primary Examiner)	(Date)	1	6B		